

CONTENTS

Acknowledgements	<i>iii</i>
List of symbols	<i>iv</i>
Abbreviations and acronyms used in the text.....	<i>viii</i>
1. Introduction	1
2. Semiconductor detectors.....	5
2.1. Materials for semiconductor detectors	6
2.2. Reverse bias p-n junction	8
2.3. Charge generation in detector.....	13
2.4. Charge transport.....	15
2.5. Ramo theory and signal formation	19
2.6. Detector geometry	21
2.7. Important detector parameters.....	23
3. Architecture of front-end electronics.....	27
3.1. Types of amplifiers.....	29
3.2. Charge sensitive amplifier.....	31
3.2.1. Ideal charge sensitive amplifier	31
3.2.2. Realistic charge sensitive amplifier	33
3.2.3. Examples of core amplifier architectures.....	37
3.2.4. Feedback configuration.....	40
3.2.5. Test injection circuit	42
3.3. Shaper.....	43
3.3.1. Signal shaping	44
3.3.2. Noise analysis	56
3.4. Noise optimization of CSA input transistor	62
3.4.1. Strong inversion region.....	63
3.4.2. Moderate and weak inversion regions	66
3.5. Aspect of fast signal processing	70
3.5.1. Pulse pile-ups at CSA output	71
3.5.2. Pole-zero cancellation circuit.....	72
3.5.3. Base line restorer	75
3.6. Further signal processing.....	80
3.6.1. Discriminators.....	83
3.6.2. Peak Detector Derandomizer	86
4. Important aspect of multichannel low noise mixed-mode integrated circuits.....	89
4.1. Noise modeling in MOS transistors	91
4.1.1. Channel thermal noise.....	91
4.1.2. Flicker noise.....	94
4.1.3. Short channel effects.....	96

4.2. Cross-talk in mixed mode circuits	98
4.2.1. Generation, transmission and reception of switching noise	98
4.2.2. Reducing the noise generation	102
4.2.3. Increasing the immunity of analog part	103
4.2.4. Isolation techniques	103
4.2.5. Summary of crosstalk reduction techniques	106
4.3. Random matching and offsets	107
4.3.1. Mismatch parameters of MOS transistors.....	109
4.3.2. Transistor matching in various processes	112
4.3.3. Current matching in MOS transistors	114
4.3.4. Random matching in circuits	115
4.3.5. Layout rules for good matching	116
4.3.6. Matching on multichip modules	118
4.3.7. Mismatch simulation using Monte Carlo analysis	119
5. Radiation damage in silicon detectors and readout electronics.....	121
5.1. Total dose effects	122
5.1.1. Displacement damage	122
5.1.2. Ionization effects.....	123
5.2. Single event effects	127
5.3. Radiation tolerant design of readout electronics	128
6. Examples of multichannel counting IC for X-ray applications.....	131
6.1. Requirements for multichannel counting systems	132
6.2. ASIC for strip detectors.....	135
6.3. Solutions for pad detectors and small array of pixel detectors	141
6.4. Solutions for pixel detectors.....	148
7. References	173